## SN5412, SN54LS12 SN7412, SN74LS12 SDLS040 TRIPLE 3-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS December 1983- Revised MARCH 1988

- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

### description

These devices contain three independent 3-input NAND gates with open-collector outputs. The open-collector outputs require pull-up resistors to perform correctly. They may be connected to other open-collector outputs to implement active-low wired-OR or active-high wired-AND functions. Open-collector devices are often used to generate higher VOH levels.

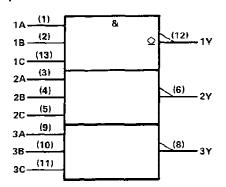
The SN5412 and SN54LS12 are characterized for operation over the full military temperature range of -55 °C to 125 °C. The SN7412 and SN74LS12 are characterized for operation from 0 °C to 70 °C.

#### FUNCTION TABLE (each gate)

	NPUT	S	OUTPUT
А	В	С	Y
н	н	H	L
L	х	X	н
x	L	x	н
х	Х	L	Н

#### logic symbol<sup>†</sup>

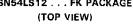
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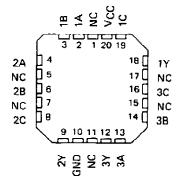


<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

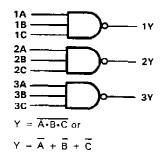
SN5412, SN54LS12 ... J OR W PACKAGE SN7412 ... N PACKAGE SN74LS12 ... D OR N PACKAGE (TOP VIEW) J₁₄⊡ v<sub>CC</sub> 1A 🗍 1B 130 1C 2A □3 120 1Y 2B □4 11D 3C 2C ₫5 10 3B 2Y 6 90 3A GND 3Y 7 8 SN54LS12 . . . FK PACKAGE





NC-No internal connection

logic diagram (positive logic)

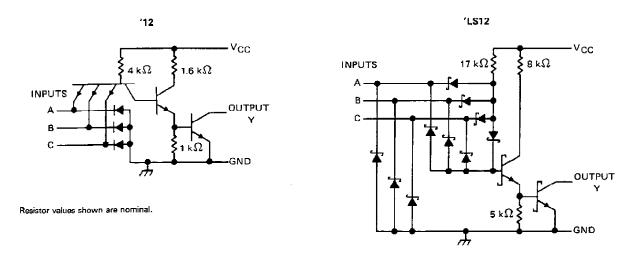


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# SN5412, SN54LS12 SN7412, SN74LS12 TRIPLE 3-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR DUTPUTS

schematics (each gate)



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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V <sub>CC</sub> (see Note	1)	7 V
Input voltage: '12		5.5 V
'LS12		7 V
Off-state output voltage		7 V
Operating free-air temperature:	SN54'	5°C to 125°C
	SN74'	0°C to 70°C
Storage temperature range		5°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.



# SN5412, SN5412 TRIPLE 3 INPUT POSITIVE NAND GATES WITH OPEN COLLECTOR OUTPUTS

		SN5412		SN7412			
	MIN	NOM	MAX	MIN	NOM	MAX	I UNIT
V <sub>CC</sub> Supply voltage	4.5	5	5,5	4.75	5	5,25	V
VIH High-level input voltage	2			2			V
VIL Low-level input voltage			0.8			0.8	v
VOH High-level output voltage			5.5			5,5	V
IOL Low-level output current			16			16	mA
TA Operating free-air temperature	- 55		125	0		70	°c

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS <sup>†</sup>	SN5412	SN7412	
		MIN TYP <sup>‡</sup> MAX	MIN TYP <sup>‡</sup> MAX	UNIT
VIK	$V_{CC} = MIN$ , $I_{I} = -12 \text{ mA}$	- 1.5	- 1.5	V
	$V_{CC} = MIN, V_{IL} = 0.8 V, V_{OH} = 5.5 V$		0.25	
<b>ю</b> н	$V_{CC} = MIN, V_{IL} = 0.7 V, V_{OH} = 5.5 V$	0.25		mA
VOL	$V_{CC} = MIN$ , $V_{IH} = 2 V$ , $I_{OL} = 16 mA$	0.2 0.4	0.2 0.4	V
h	V <sub>CC</sub> = MAX, V <sub>I</sub> = 5.5 V	1	1	mA
IH	$V_{CC} = MAX,  V_I = 2.4 V$	40	40	μA
հե	$V_{CC} = MAX, V_I = 0.4 V$	- 1.6	- 1.6	mA
ССН	$V_{CC} = MAX, V_I = 0$	3 6	3 6	mA
CCL	$V_{CC} = MAX,  V_{I} = 4.5 V$	9 16.5	9 16.5	mA

<sup>†</sup>For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. <sup>‡</sup>All typical values are at  $V_{CC} = 5 V$ ,  $T_A = 25 °C$ .

# switching characteristics, $V_{CC} = 5 V$ , $T_A = 25^{\circ}C$ (see note 2)

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PARAMETER	FROM (INPUT)	το (ουτρυτ)	TEST CONDITIONS		MIN	Түр	MAX	UNIT
<sup>t</sup> PLH	A, BorC		$R_L = 4 k\Omega_r$	CL = 15 pF		35	45	ns
<sup>t</sup> PHL	— А, в ог С		RL = 400 Ω,	CL = 15 pF		8	15	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



# SN54LS12, SN74LS12 TRIPLE 3-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

### recommended operating conditions

		SN54LS12			\$N74LS12		
	MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC Supply voltage	4.5	5	5.5	4.75	5	5.25	V
VIH High-level input voltage	2			2			V
VIL · Low-level input voltage			0,7			0.8	v
VOH High-level output voltage			5.5			5.5	V
IOL Low-level output current			4			8	mΑ
TA Operating free-air temperature	- 55		125	0		70	°c

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		SN54LS12	SN74LS12	UNIT
	TEST CONDITIONS †	MIN TYP‡ MAX	MIN TYPE MAX	
Vik	V <sub>CC</sub> = MIN, I <sub>1</sub> = 18 mA	- 1.5	- 1.5	V
юн	V <sub>CC</sub> = MIN, V <sub>IL</sub> = MAX, V <sub>OH</sub> = 5.5 V	0.1	0.1	mА
	$V_{CC} = MIN$ , $V_{IH} = 2V$ , $t_{OL} = 4 mA$	0.25 0.4	0.25 0.4	v
VOL	V <sub>CC</sub> = MIN, V <sub>IH</sub> ≃ 2 V, I <sub>OL</sub> = 8 mA		0.35 0.5	
11	V <sub>CC</sub> = MAX, V <sub>1</sub> = 7 V	0.1	0.1	mA
	V <sub>CC</sub> = MAX, V <sub>1</sub> = 2.7 V	20	20	μA
	V <sub>CC</sub> = MAX, V <sub>1</sub> = 0.4 V	- 0.4	- 0.4	mA
Іссн	V <sub>CC</sub> = MAX, V <sub>1</sub> = 0	- 0.7 1.4	0,7 1.4	mA
ICCL	V <sub>CC</sub> = MAX, V <sub>I</sub> = 4.5 V	1,8 3.3	1.8 3,3	mΑ

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. ‡ All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C.

# switching characteristics, V<sub>CC</sub> = 5 V, T<sub>A</sub> = $25^{\circ}$ C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	ΜΙΝ ΤΥΡ	ΜΑΧ	UNIT
<sup>t</sup> PLH	A Bor C	Y	$R_L = 2 k\Omega$ , $C_L = 15 pF$	17	32	ńs
<sup>t</sup> PHL	A, BorC	-		15	28	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

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